

<b>Notice of References Cited</b>	Application/Control No. 10/584,218	Applicant(s)/Patent Under Reexamination MIYACHI ET AL.	
	Examiner Sean P. Cullen, Ph.D.	Art Unit 1725	Page 1 of 1

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*	C	US-6,053,953 A	04-2000	Tomiyama et al.	29/623.1
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	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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